

**Amendments to the Claims:**

This listing of claims will replace all prior versions, and listings, of claims in the application:

**Listing of Claims:**

1. (Currently Amended) A method for estimating repair accuracy of a ~~mask shop~~ comprising the steps of:
  - providing a mask having a light-shielding layer with a pattern of a plurality of lines, each of which has a defect;
  - ~~using the mask shop to repair~~ repairing the defects, whereby contaminated areas are formed in the vicinity of areas where the defects are repaired;
  - measuring first light intensities of the contaminated areas, and second and third light intensities of two sides of the contaminated areas; and
  - calculating ratios of means of the second and third light intensities to the first light intensities for estimating the repair accuracy.
2. (Currently Amended) The method as claimed in claim 1 further comprising the step of:
  - calculating a mean and  $3[\delta]\sigma$  value of the ratios.
3. (Original) The method as claimed in claim 1 wherein the lines comprise a plurality of vertical and horizontal lines.
4. (Original) The method as claimed in claim 3 wherein widths of the

lines range from  $0.5\mu\text{m}$  to  $2\mu\text{m}$ .

5. (Original) The method as claimed in claim 1 wherein widths of the defects along the lines range from  $0.3\mu\text{m}$  to  $1.5\mu\text{m}$ .

6. (Original) The method as claimed in claim 1 wherein the defects are indentations on the lines.

7. (Original) The method as claimed in claim 1 wherein the light-shielding layer is a chrome layer.